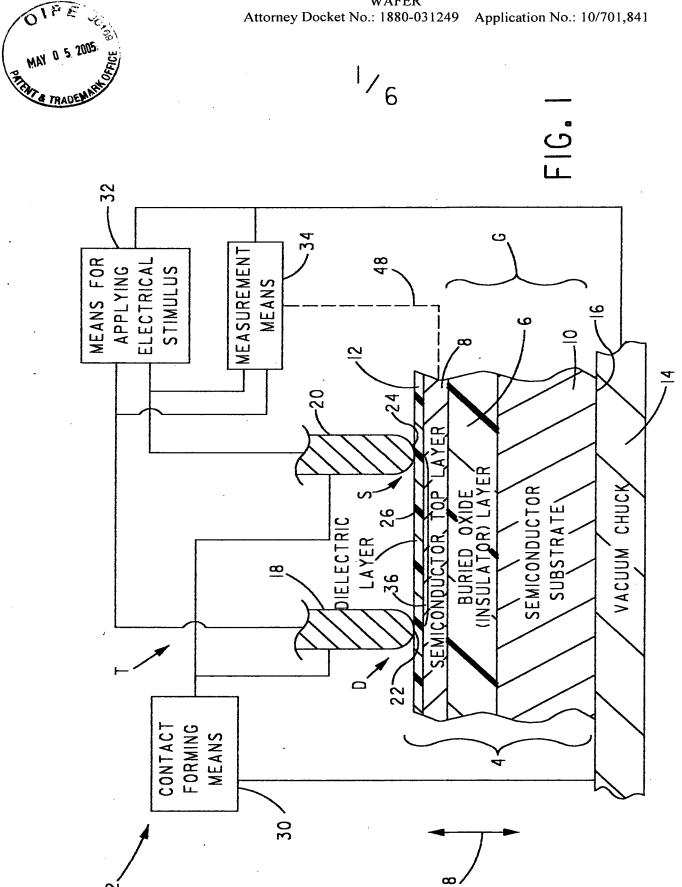
Inventor: Robert J. Hillard

"METHOD OF ELECTRICAL CHARACTERIZATION OF A SILICON-ON-INSULATOR (SOI)

WAFER"



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"METHOD OF ELECTRICAL CHARACTERIZATION OF A SILICON-ON-INSULATOR (SOI)

WAFER"

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Attorney Docket No.: 1880-031249 Application No.: 10/701,841



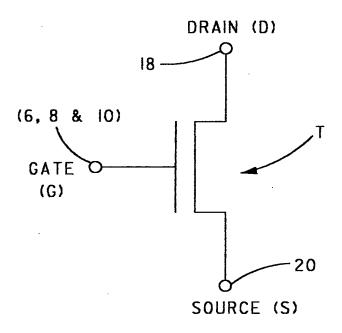


FIG. 2

WAFER"
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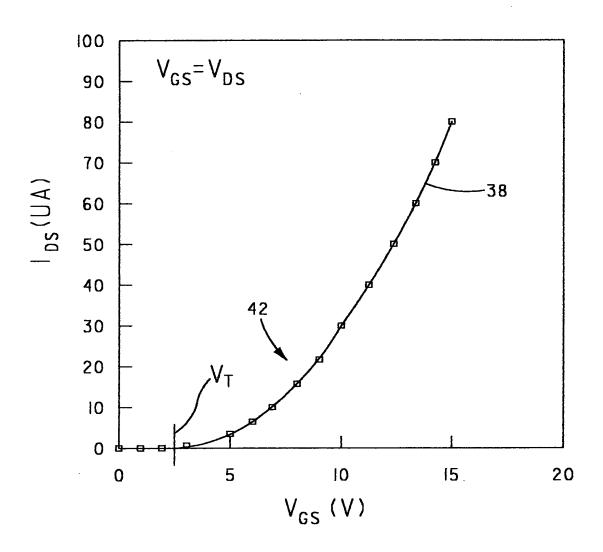


FIG. 3

Attorney Docket No.: 1880-031249 Application No.: 10/701,841

⁴/6

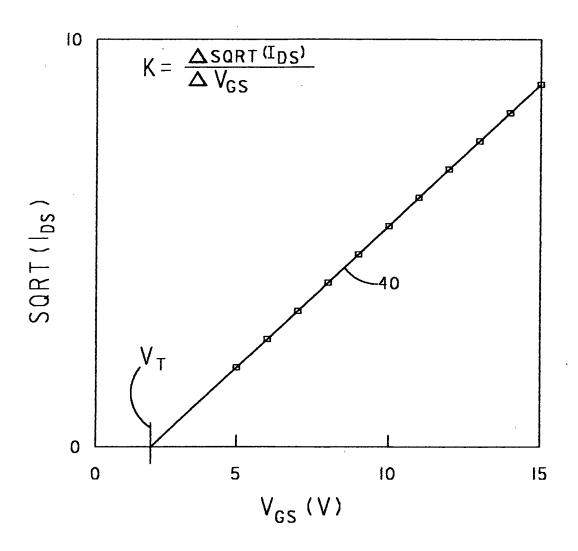


FIG. 4

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⁵/6

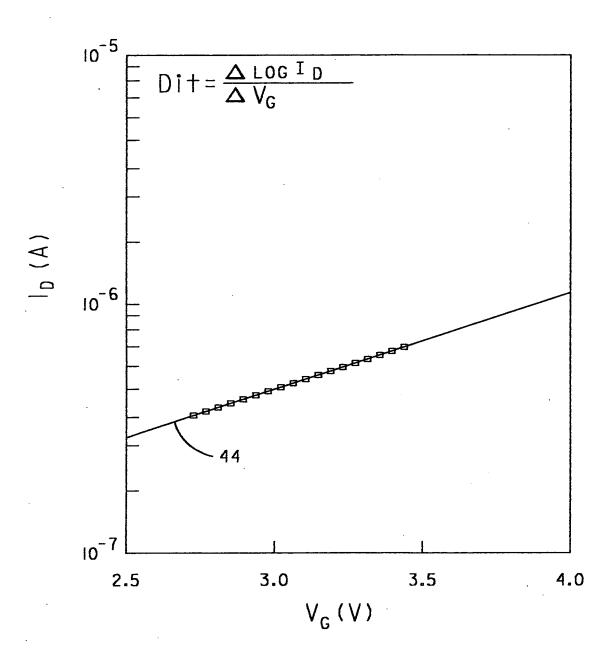


FIG. 5

Inventor: Robert J. Hillard "METHOD OF ELECTRICAL CHARACTERIZATION OF A SILICON-ON-INSULATOR (SOI)
WAFER"
Attorney Docket No.: 1880-031249 Application No.: 10/701,841

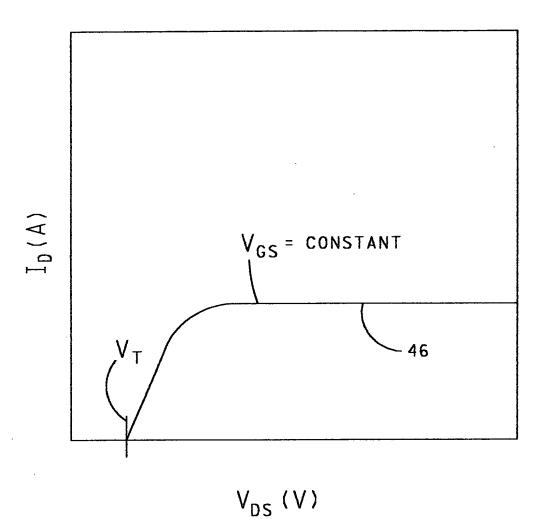


FIG. 6